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#### Intel - 5SGXEBBR1H43C2LN Datasheet



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Details	
Product Status	Obsolete
Number of LABs/CLBs	359200
Number of Logic Elements/Cells	952000
Total RAM Bits	53248000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1760-BBGA, FCBGA
Supplier Device Package	1760-HBGA (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxebbr1h43c2ln

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This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)

Symbol	Description	Condition	Min <sup>(4)</sup>	Тур	Max <sup>(4)</sup>	Unit
	Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades)	_	0.87	0.9	0.93	V
V <sub>CC</sub>	Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) <sup>(3)</sup>	_	0.82	0.85	0.88	V
V <sub>CCPT</sub>	Power supply for programmable power technology	_	1.45	1.50	1.55	V
V <sub>CC_AUX</sub>	Auxiliary supply for the programmable power technology	_	2.375	2.5	2.625	V
VI (1)	I/O pre-driver (3.0 V) power supply	_	2.85	3.0		V
V <sub>CCPD</sub> <sup>(1)</sup>	I/O pre-driver (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (3.0 V) power supply		2.85	3.0	3.15	V
	I/O buffers (2.5 V) power supply	_	2.375	2.5	2.625	V
	I/O buffers (1.8 V) power supply		1.71	1.8	1.89	V
V <sub>CCIO</sub>	I/O buffers (1.5 V) power supply	_	1.425	1.5	1.575	V
	I/O buffers (1.35 V) power supply	_	1.283	1.35	1.45	V
	I/O buffers (1.25 V) power supply	_	1.19	1.25	1.31	V
	I/O buffers (1.2 V) power supply	_	1.14	1.2	1.26	V
	Configuration pins (3.0 V) power supply	_	2.85	3.0	1.575 1.45 1.31 1.26 3.15	V
V <sub>CCPGM</sub>	Configuration pins (2.5 V) power supply	_	2.375	2.5	2.625	V
	Configuration pins (1.8 V) power supply	_	1.71	1.8	1.89	V
V <sub>CCA_FPLL</sub>	PLL analog voltage regulator power supply	_	2.375	2.5	2.625	V
V <sub>CCD_FPLL</sub>	PLL digital voltage regulator power supply	_	1.45	1.5	1.55	V
V <sub>CCBAT</sub> (2)	Battery back-up power supply (For design security volatile key register)	_	1.2	_	3.0	V
VI	DC input voltage	_	-0.5	_	3.6	V
V <sub>0</sub>	Output voltage	—	0	—	V <sub>CCIO</sub>	V
т	Operating junction temperature	Commercial	0	—	85	°C
TJ	Operating junction temperature	Industrial	-40	_	100	°C

#### I/O Pin Leakage Current

Table 9 lists the Stratix V I/O pin leakage current specifications.

Table 9. I/	0 Pin Leakage	<b>Current for Stratix </b>	/ Devices <sup>(1)</sup>
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Symbol	Description	Conditions	Min	Тур	Max	Unit
I <sub>I</sub>	Input pin	$V_I = 0 V \text{ to } V_{CCIOMAX}$	-30	—	30	μA
I <sub>0Z</sub>	Tri-stated I/O pin	$V_0 = 0 V$ to $V_{CCIOMAX}$	-30		30	μA

#### Note to Table 9:

(1) If  $V_0 = V_{CCIO}$  to  $V_{CCIOMax}$ , 100  $\mu$ A of leakage current per I/O is expected.

#### **Bus Hold Specifications**

Table 10 lists the Stratix V device family bus hold specifications.

Table 10. Bus Hold Parameters for Stratix V Devices

		Conditions					Va	CI0	-		-		
Parameter	Symbol		1.2 V		1.5 V		1.8 V		2.5 V		3.0 V		Unit
			Min	Max									
Low sustaining current	I <sub>SUSL</sub>	V <sub>IN</sub> > V <sub>IL</sub> (maximum)	22.5	_	25.0	_	30.0	_	50.0	_	70.0	_	μA
High sustaining current	I <sub>SUSH</sub>	V <sub>IN</sub> < V <sub>IH</sub> (minimum)	-22.5	_	-25.0	_	-30.0	_	-50.0	_	-70.0	_	μA
Low overdrive current	I <sub>odl</sub>	$0V < V_{IN} < V_{CCIO}$	_	120	_	160	_	200	_	300	_	500	μA
High overdrive current	I <sub>odh</sub>	0V < V <sub>IN</sub> < V <sub>CCI0</sub>		-120		-160	_	-200		-300	_	-500	μA
Bus-hold trip point	V <sub>trip</sub>	_	0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

#### **On-Chip Termination (OCT) Specifications**

If you enable OCT calibration, calibration is automatically performed at power-up for I/Os connected to the calibration block. Table 11 lists the Stratix V OCT termination calibration accuracy specifications.

Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices <sup>(1)</sup> (Part 1 of 2)

			Calibration Accuracy					
Symbol	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit	
25-Ω R <sub>S</sub>	Internal series termination with calibration (25- $\Omega$ setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%	

I/O Standard	V <sub>IL(DC)</sub> (V)		V <sub>IH(D</sub>	<sub>C)</sub> (V)	V <sub>IL(AC)</sub> (V)	V <sub>IH(AC)</sub> (V)	V <sub>ol</sub> (V)	V <sub>oh</sub> (V)	I (mA)	I <sub>oh</sub>
i/U Stanuaru	Min	Max	Min	Max	Max	Min	Max	Min	l <sub>oi</sub> (mA)	(mA)
HSTL-18 Class I	_	V <sub>REF</sub> – 0.1	V <sub>REF</sub> + 0.1	_	$V_{REF} - 0.2$	V <sub>REF</sub> + 0.2	0.4	V <sub>CCIO</sub> – 0.4	8	-8
HSTL-18 Class II	_	V <sub>REF</sub> – 0.1	V <sub>REF</sub> + 0.1	_	V <sub>REF</sub> - 0.2	V <sub>REF</sub> + 0.2	0.4	V <sub>CCIO</sub> – 0.4	16	-16
HSTL-15 Class I	_	V <sub>REF</sub> – 0.1	V <sub>REF</sub> + 0.1	_	V <sub>REF</sub> - 0.2	V <sub>REF</sub> + 0.2	0.4	V <sub>CCIO</sub> – 0.4	8	-8
HSTL-15 Class II	_	V <sub>REF</sub> – 0.1	V <sub>REF</sub> + 0.1	_	V <sub>REF</sub> - 0.2	V <sub>REF</sub> + 0.2	0.4	V <sub>CCIO</sub> – 0.4	16	-16
HSTL-12 Class I	-0.15	V <sub>REF</sub> – 0.08	V <sub>REF</sub> + 0.08	V <sub>CCIO</sub> + 0.15	V <sub>REF</sub> – 0.15	V <sub>REF</sub> + 0.15	0.25* V <sub>CCI0</sub>	0.75* V <sub>CCI0</sub>	8	-8
HSTL-12 Class II	-0.15	V <sub>REF</sub> – 0.08	V <sub>REF</sub> + 0.08	V <sub>CCIO</sub> + 0.15	V <sub>REF</sub> – 0.15	V <sub>REF</sub> + 0.15	0.25* V <sub>CCIO</sub>	0.75* V <sub>CCI0</sub>	16	-16
HSUL-12	_	V <sub>REF</sub> – 0.13	V <sub>REF</sub> + 0.13	_	V <sub>REF</sub> – 0.22	V <sub>REF</sub> + 0.22	0.1* V <sub>CCIO</sub>	0.9* V <sub>CCI0</sub>	_	_

#### Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 2 of 2)

Table 20. Differential SSTL I/O Standards for Stratix V Devices

I/O Standard		V <sub>CCIO</sub> (V)			<sub>G(DC)</sub> (V)		V <sub>X(AC)</sub> (V)		V <sub>swing(</sub> ,	<sub>AC)</sub> (V)
ijo Stanuaru	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V <sub>CCI0</sub> + 0.6	V <sub>CCI0</sub> /2- 0.2	_	V <sub>CCI0</sub> /2 + 0.2	0.62	V <sub>CCI0</sub> + 0.6
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V <sub>CCI0</sub> + 0.6	V <sub>CCI0</sub> /2- 0.175	_	V <sub>CCI0</sub> /2 + 0.175	0.5	V <sub>CCI0</sub> + 0.6
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	(1)	V <sub>CCI0</sub> /2- 0.15	_	V <sub>CCI0</sub> /2 + 0.15	0.35	_
SSTL-135 Class I, II	1.283	1.35	1.45	0.2	(1)	V <sub>CCI0</sub> /2- 0.15	V <sub>CCI0</sub> /2	V <sub>CCI0</sub> /2 + 0.15	2(V <sub>IH(AC)</sub> - V <sub>REF</sub> )	2(V <sub>IL(AC)</sub> - V <sub>REF</sub> )
SSTL-125 Class I, II	1.19	1.25	1.31	0.18	(1)	V <sub>CCI0</sub> /2- 0.15	V <sub>CCI0</sub> /2	V <sub>CCI0</sub> /2 + 0.15	2(V <sub>IH(AC)</sub> - V <sub>REF</sub> )	_
SSTL-12 Class I, II	1.14	1.2	1.26	0.18	_	V <sub>REF</sub> -0.15	V <sub>CCI0</sub> /2	V <sub>REF</sub> + 0.15	-0.30	0.30

Note to Table 20:

(1) The maximum value for  $V_{SWING(DC)}$  is not defined. However, each single-ended signal needs to be within the respective single-ended limits  $(V_{IH(DC)} \text{ and } V_{IL(DC)})$ .

I/O	V <sub>CCIO</sub> (V)			V <sub>DIF(I</sub>	<sub>DC)</sub> (V)		V <sub>X(AC)</sub> (V)			V <sub>CM(DC)</sub> (V)			V <sub>DIF(AC)</sub> (V)	
Standard	Min	Тур	Max	Min	Max	Min	Тур	Max	Min	Тур	Max	Min	Max	
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	_	0.78	_	1.12	0.78	_	1.12	0.4	_	
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	_	0.68	_	0.9	0.68	_	0.9	0.4	_	

Table 26 shows the approximate maximum data rate using the 10G PCS.

Table 26. Stratix V 10G PCS Approximate Maximum Data Rate (1)
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Mada (2)	Transceiver	PMA Width	64	40	40	40	32	32		
Mode <sup>(2)</sup>	Speed Grade	PCS Width	64	66/67	50	40	64/66/67	32		
	1	C1, C2, C2L, I2, I2L core speed grade	14.1	14.1	10.69	14.1	13.6	13.6		
2	2	C1, C2, C2L, I2, I2L core speed grade	12.5	12.5	10.69	12.5	12.5	12.5		
	2	C3, I3, I3L core speed grade	12.5	12.5	10.69	12.5	10.88	10.88		
FIFO or Register		C1, C2, C2L, I2, I2L core speed grade	8.5 Gbps							
	3	C3, I3, I3L core speed grade								
	3	C4, I4 core speed grade								
		I3YY core speed grade			10.31	25 Gbps				

Notes to Table 26:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

### Table 28. Transceiver Specifications for Stratix V GT Devices (Part 2 of 5)<sup>(1)</sup>

Symbol/	Conditions		Transceive Speed Grade			Fransceive Deed Grade		Unit
Description		Min	Тур	Max	Min	Тур	Max	Ī
	100 Hz			-70			-70	
Transmitter REFCLK	1 kHz		_	-90	_	_	-90	-
Phase Noise (622	10 kHz		_	-100	_	_	-100	dBc/Hz
MHz) <sup>(18)</sup>	100 kHz		—	-110	_	—	-110	-
	$\geq$ 1 MHz		—	-120	_	—	-120	-
Transmitter REFCLK Phase Jitter (100 MHz) <sup>(15)</sup>	10 kHz to 1.5 MHz (PCIe)		_	3	_		3	ps (rms)
RREF <sup>(17)</sup>	—		1800 ± 1%	_	_	1800 ± 1%	_	Ω
Transceiver Clocks								
fixedclk <b>clock</b> frequency	PCIe Receiver Detect		100 or 125	_	_	100 or 125	_	MHz
Reconfiguration clock (mgmt_clk_clk) frequency	_	100	_	125	100	_	125	MHz
Receiver				•				
Supported I/O Standards	—		1.4-V PCMI	_, 1.5-V PCM	L, 2.5-V PCI	ML, LVPEC	L, and LVDS	3
Data rate (Standard PCS) <sup>(21)</sup>	GX channels	600	_	8500	600	_	8500	Mbps
Data rate (10G PCS) <sup>(21)</sup>	GX channels	600	_	12,500	600	_	12,500	Mbps
Data rate	GT channels	19,600	—	28,050	19,600	—	25,780	Mbps
Absolute V <sub>MAX</sub> for a receiver pin <sup>(3)</sup>	GT channels	_	_	1.2	_	_	1.2	V
Absolute V <sub>MIN</sub> for a receiver pin	GT channels	-0.4	_	_	-0.4		_	V
Maximum peak-to-peak	GT channels	_	—	1.6	—	—	1.6	V
differential input voltage V <sub>ID</sub> (diff p-p) before device configuration <sup>(20)</sup>	GX channels				(8)			
	GT channels							
Maximum peak-to-peak differential input voltage $V_{ID}$ (diff p-p) after device configuration ( <sup>16</sup> ), ( <sup>20</sup> )	V <sub>CCR_GTB</sub> = 1.05 V (V <sub>ICM</sub> = 0.65 V)	—	-	2.2	_	_	2.2	V
oomguration ( ), ( )	GX channels		•	•	(8)			
Minimum differential	GT channels	200	_		200			mV
eye opening at receiver serial input pins <sup>(4)</sup> , <sup>(20)</sup>	GX channels				(8)			

Figure 6 shows the Stratix V DC gain curves for GT channels.

Figure 6. DC Gain Curves for GT Channels

#### **Transceiver Characterization**

This section summarizes the Stratix V transceiver characterization results for compliance with the following protocols:

- Interlaken
- 40G (XLAUI)/100G (CAUI)
- 10GBase-KR
- QSGMII
- XAUI
- SFI
- Gigabit Ethernet (Gbe / GIGE)
- SPAUI
- Serial Rapid IO (SRIO)
- CPRI
- OBSAI
- Hyper Transport (HT)
- SATA
- SAS
- CEI

## **PLL Specifications**

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to  $85^{\circ}$ C) and the industrial junction temperature range (-40° to  $100^{\circ}$ C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	_	800 (1)	MHz
f <sub>IN</sub>	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	_	800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	_	650 <sup>(1)</sup>	MHz
f <sub>INPFD</sub>	Input frequency to the PFD	5	—	325	MHz
f <sub>finpfd</sub>	Fractional Input clock frequency to the PFD	50	—	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f <sub>VCO</sub>	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	_	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
t <sub>einduty</sub>	Input clock or external feedback clock input duty cycle	40		60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	_	717 <sup>(2)</sup>	MHz
f <sub>out</sub>	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	_	_	650 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	_	_	580 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	_	_	800 (2)	MHz
f <sub>out_ext</sub>	Output frequency for an external clock output (C3, I3, I3L speed grades)	_	_	667 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	_	_	553 <sup>(2)</sup>	MHz
t <sub>outduty</sub>	Duty cycle for a dedicated external clock output (when set to <b>50%</b> )	45	50	55	%
t <sub>FCOMP</sub>	External feedback clock compensation time	_	—	10	ns
f <sub>dyconfigclk</sub>	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	_	_	100	MHz
t <sub>LOCK</sub>	Time required to lock from the end-of-device configuration or deassertion of areset	_	_	1	ms
t <sub>olock</sub>	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	_	_	1	ms
	PLL closed-loop low bandwidth		0.3	—	MHz
f <sub>CLBW</sub>			1.5		MHz
	PLL closed-loop high bandwidth (7)		4	—	MHz
t <sub>PLL_PSERR</sub>	Accuracy of PLL phase shift			±50	ps
t <sub>areset</sub>	Minimum pulse width on the areset signal	10	_		ns

#### Table 31. PLL Specifications for Stratix V Devices (Part 3 of 3)

Symbol	Parameter Besolution of VCO frequency (fuero = 100 MHz) 39		Тур	Max	Unit
f <sub>RES</sub>	Resolution of VCO frequency ( $f_{INPFD} = 100 \text{ MHz}$ )	390625	5.96	0.023	Hz

#### Notes to Table 31:

(1) This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.

(2) This specification is limited by the lower of the two: I/O  $f_{MAX}$  or  $f_{OUT}$  of the PLL.

- (3) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source < 120 ps.
- (4)  $f_{REF}$  is fIN/N when N = 1.
- (5) Peak-to-peak jitter with a probability level of 10<sup>-12</sup> (14 sigma, 99.9999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 44 on page 52.
- (6) The cascaded PLL specification is only applicable with the following condition: a. Upstream PLL: 0.59Mhz ≤ Upstream PLL BW < 1 MHz b. Downstream PLL: Downstream PLL BW > 2 MHz
- (7) High bandwidth PLL settings are not supported in external feedback mode.
- (8) The external memory interface clock output jitter specifications use a different measurement method, which is available in Table 42 on page 50.
- (9) The VCO frequency reported by the Quartus II software in the PLL Usage Summary section of the compilation report takes into consideration the VCO post-scale counter K value. Therefore, if the counter K has a value of 2, the frequency reported can be lower than the f<sub>VCO</sub> specification.
- (10) This specification only covers fractional PLL for low bandwidth. The  $f_{VCO}$  for fractional value range 0.05 0.95 must be  $\geq$  1000 MHz, while  $f_{VCO}$  for fractional value range 0.20 0.80 must be  $\geq$  1200 MHz.
- (11) This specification only covered fractional PLL for low bandwidth. The  $f_{VC0}$  for fractional value range 0.05-0.95 must be  $\geq$  1000 MHz.
- (12) This specification only covered fractional PLL for low bandwidth. The  $f_{VC0}$  for fractional value range 0.20-0.80 must be  $\geq$  1200 MHz.

#### **DSP Block Specifications**

Table 32 lists the Stratix V DSP block performance specifications.

			I	Peforman	ce			
Mode	C1	C2, C2L	12, 12L	C3	13, 13L, 13YY	C4	14	Unit
		Modes ι	ising one	DSP				4
Three 9 x 9	600	600	600	480	480	420	420	MHz
One 18 x 18	600	600	600	480	480	420	400	MHz
Two partial 18 x 18 (or 16 x 16)	600	600	600	480	480	420	400	MHz
One 27 x 27	500	500	500	400	400	350	350	MHz
One 36 x 18	500	500	500	400	400	350	350	MHz
One sum of two 18 x 18(One sum of 2 16 x 16)	500	500	500	400	400	350	350	MHz
One sum of square	500	500	500	400	400	350	350	MHz
One 18 x 18 plus 36 (a x b) + c	500	500	500	400	400	350	350	MHz
		Modes u	sing two l	DSPs	1		•	1
Three 18 x 18	500	500	500	400	400	350	350	MHz
One sum of four 18 x 18	475	475	475	380	380	300	300	MHz
One sum of two 27 x 27	465	465	450	380	380	300	290	MHz
One sum of two 36 x 18	475	475	475	380	380	300	300	MHz
One complex 18 x 18	500	500	500	400	400	350	350	MHz
One 36 x 36	475	475	475	380	380	300	300	MHz

#### Table 32. Block Performance Specifications for Stratix V DSP Devices (Part 1 of 2)

		Resour	ces Used			Pe	erforman	ce			
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	Unit
	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port with the read-during-write option set to <b>Old Data</b> , all supported widths	0	1	525	525	455	400	525	455	400	MHz
M20K Block	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz

#### Table 33. Memory Block Performance Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50**% output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F<sub>MAX</sub>.

(3) The F<sub>MAX</sub> specification is only achievable with Fitter options, MLAB Implementation In 16-Bit Deep Mode enabled.

## **Temperature Sensing Diode Specifications**

Table 34 lists the internal TSD specification.

#### **Table 34. Internal Temperature Sensing Diode Specification**

Temperature Range	Accuracy	Offset Calibrated Option	Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
-40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

	Table 35.	External	Temperature	Sensing Diode	e Specifications	for Stratix V Devices
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Description	Min	Тур	Max	Unit
I <sub>bias</sub> , diode source current	8	—	200	μΑ
V <sub>bias,</sub> voltage across diode	0.3	—	0.9	V
Series resistance	—	—	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	—

0b.al	Oanditiana		C1		C2,	C2L, I	2, I2L	C3,	13, 131	., <b>I</b> 3YY		C4,I	4	Unit
Symbol	Conditions	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
Transmitter				<u>.</u>						<u>.</u>				
	SERDES factor J = 3 to 10 <sup>(9)</sup> , <sup>(11)</sup> , <sup>(12)</sup> , <sup>(13)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	(6)		1600	(6)		1434	(6)		1250	(6)		1050	Mbps
	SERDES factor J $\geq 4$													
True Differential I/O Standards	LVDS TX with DPA <sup>(12)</sup> , <sup>(14)</sup> , <sup>(15)</sup> , <sup>(16)</sup>	(6)	_	1600	(6)	_	1600	(6)	_	1600	(6)	_	1250	Mbps
- f <sub>HSDR</sub> (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f <sub>HSDR</sub> (data rate) <sup>(10)</sup>	SERDES factor J = 4 to 10 $(17)$	(6)		1100	(6)		1100	(6)		840	(6)		840	Mbps
t <sub>x Jitter</sub> - True Differential	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_		160	_	_	160			160	_	_	160	ps
I/O Standards	Total Jitter for Data Rate < 600 Mbps	_	_	0.1	_	_	0.1	_	_	0.1	_	_	0.1	UI
t <sub>x Jitter</sub> - Emulated Differential I/O Standards	Total Jitter for Data Rate 600 Mbps - 1.25 Gbps	_		300	_		300	_	_	300	_		325	ps
with Three External Output Resistor Network	Total Jitter for Data Rate < 600 Mbps	_		0.2			0.2			0.2	_		0.25	UI

## Table 36. High-Speed I/O Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 4)

i ani o o o i i i i gii	-Speed I/U Specifica		C1				2, I2L		-	., I3YY		C4,I	A	
Symbol	Conditions				-	-	-		-	-		-		Unit
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
t <sub>duty</sub>	Transmitter output clock duty cycle for both True and Emulated Differential I/O Standards	45	50	55	45	50	55	45	50	55	45	50	55	%
	True Differential I/O Standards	_	_	160	_	_	160	_	_	200	_	_	200	ps
t <sub>rise</sub> & t <sub>fall</sub>	Emulated Differential I/O Standards with three external output resistor networks			250			250			250			300	ps
	True Differential I/O Standards	_	_	150	_	_	150	_	_	150	_	_	150	ps
TCCS	Emulated Differential I/O Standards	_		300	_	_	300	_	_	300	_	_	300	ps
Receiver														
	SERDES factor J = 3 to 10 (11), (12), (13), (14), (15), (16)	150		1434	150	_	1434	150	_	1250	150	_	1050	Mbps
True Differential I/O Standards	SERDES factor J ≥ 4 LVDS RX with DPA (12), (14), (15), (16)	150		1600	150		1600	150		1600	150		1250	Mbps
- f <sub>HSDRDPA</sub> (data rate)	SERDES factor J = 2, uses DDR Registers	(6)		(7)	(6)	_	(7)	(6)	_	(7)	(6)	_	(7)	Mbps
	SERDES factor J = 1, uses SDR Register	(6)		(7)	(6)		(7)	(6)		(7)	(6)		(7)	Mbps

## Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 3 of 4)

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

#### Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 40:

(1) The typical value equals the average of the minimum and maximum values.

(2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a -2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is [625 ps + (10 × 10 ps) ± 20 ps] = 725 ps ± 20 ps.

Table 41 lists the DQS phase shift error for Stratix V devices.

Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock (t<sub>DQS\_PSERR</sub>) for Stratix V Devices <sup>(1)</sup>

Number of DQS Delay Buffers	C1	C2, C2L, I2, I2L	C3, I3, I3L, I3YY	C4,14	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

Notes to Table 41:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a -2 speed grade is  $\pm 78$  ps or  $\pm 39$  ps.

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

Clock Network	Parameter	Symbol	C	1	C2, C2L	, 12, 12L	C3, I3, I3L, I3YY C4,I4		,14	Unit	
	NGLWUIK		-	Min	Max	Min	Max	Min	Max	Min	Max
	Clock period jitter	t <sub>JIT(per)</sub>	-50	50	-50	50	-55	55	-55	55	ps
Regional	Cycle-to-cycle period jitter	$t_{\rm JIT(cc)}$	-100	100	-100	100	-110	110	-110	110	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-50	50	-50	50	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	t <sub>JIT(per)</sub>	-75	75	-75	75	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-150	150	-150	150	-165	165	-165	165	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-75	75	-75	75	-90	90	-90	90	ps

Symbol	Description	Min	Max	Unit
t <sub>JPH</sub>	JTAG port hold time	5	—	ns
t <sub>JPCO</sub>	JTAG port clock to output	—	11 <sup>(1)</sup>	ns
t <sub>JPZX</sub>	JTAG port high impedance to valid output	—	14 <sup>(1)</sup>	ns
t <sub>JPXZ</sub>	JTAG port valid output to high impedance	—	<b>1</b> 4 <sup>(1)</sup>	ns

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Notes to Table 46:

(1) A 1 ns adder is required for each V<sub>CCI0</sub> voltage step down from 3.0 V. For example,  $t_{JPC0} = 12$  ns if V<sub>CCI0</sub> of the TDO I/O bank = 2.5 V, or 13 ns if it equals 1.8 V.

(2) The minimum TCK clock period is 167 ns if VCCBAT is within the range 1.2V-1.5V when you perform the volatile key programming.

## **Raw Binary File Size**

For the POR delay specification, refer to the "POR Delay Specification" section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices".

Table 47 lists the uncompressed raw binary file (.rbf) sizes for Stratix V devices.

Family	Device	Package	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits) <sup>(4), (5)</sup>
	ECCVA2	H35, F40, F35 <sup>(2)</sup>	213,798,880	562,392
	5SGXA3	H29, F35 <sup>(3)</sup>	137,598,880	564,504
	5SGXA4	_	213,798,880	563,672
	5SGXA5	_	269,979,008	562,392
	5SGXA7	_	269,979,008	562,392
Stratix V GX	5SGXA9	_	342,742,976	700,888
	5SGXAB	_	342,742,976	700,888
	5SGXB5	_	270,528,640	584,344
	5SGXB6	_	270,528,640	584,344
	5SGXB9	_	342,742,976	700,888
	5SGXBB	_	342,742,976	700,888
Stratix V GT	5SGTC5	_	269,979,008	562,392
	5SGTC7	—	269,979,008	562,392
	5SGSD3	_	137,598,880	564,504
	5SGSD4	F1517	213,798,880	563,672
Ctratic V CC	556504	_	137,598,880	564,504
Stratix V GS	5SGSD5	_	213,798,880	563,672
	5SGSD6	_	293,441,888	565,528
	5SGSD8	_	293,441,888	565,528

Table 47. Uncompressed .rbf Sizes for Stratix V Devices

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Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is more than 1.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	_	μS
t <sub>STATUS</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5		ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	N-1/f <sub>DCLK</sub> <sup>(5)</sup>		S
t <sub>CH</sub>	DCLK high time	$0.45  imes 1/f_{MAX}$		S
t <sub>CL</sub>	DCLK low time	$0.45\times1/f_{MAX}$		S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>		S
f	DCLK frequency (FPP ×8/×16)	—	125	MHz
f <sub>MAX</sub>	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>R</sub>	Input rise time	—	40	ns
t <sub>F</sub>	Input fall time	—	40	ns
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(3)</sup>	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

#### Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (5) N is the  ${\tt DCLK}\mbox{-to-DATA}$  ratio and  $f_{{\tt DCLK}}$  is the  ${\tt DCLK}$  frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

## **Active Serial Configuration Timing**

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

Table 52.	DCLK Frequency	Specification in the <i>l</i>	AS Configuration Scheme	(1), (2)
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Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

#### Notes to Table 52:

(1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

(2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.





#### Notes to Figure 14:

- (1) If you are using AS  $\times 4$  mode, this signal represents the AS\_DATA[3..0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 53 lists the timing parameters for AS  $\times 1$  and AS  $\times 4$  configurations in Stratix V devices.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CO</sub>	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
t <sub>SU</sub>	Data setup time before falling edge on DCLK	1.5	—	ns
t <sub>H</sub>	Data hold time after falling edge on DCLK	0	—	ns

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CD2UM</sub>	CONF_DONE high to user mode $(3)$	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	—
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	t <sub>cd2cu</sub> + (8576 × clkusr period)	_	—

Table 53. AS Timing Parameters for AS  $\times$ 1 and AS  $\times$ 4 Configurations in Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 53:

(1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(2) t<sub>CF2CD</sub>, t<sub>CF2ST0</sub>, t<sub>CF2ST0</sub>, t<sub>CF6</sub>, t<sub>STATUS</sub>, and t<sub>CF2ST1</sub> timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.

(3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

## **Passive Serial Configuration Timing**

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform <sup>(1)</sup>



#### Notes to Figure 15:

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds <code>nSTATUS</code> low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATAO is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

Parameter	Available	Min	Fast	Model				Slow N	lodel			
(1)	Settings	<b>Offset</b> (2)	Industrial	Commercial	C1	C2	C3	C4	12	13, 13YY	14	Unit
D3	8	0	1.587	1.699	2.793	2.793	2.992	3.192	2.811	3.047	3.257	ns
D4	64	0	0.464	0.492	0.838	0.838	0.924	1.011	0.843	0.920	1.006	ns
D5	64	0	0.464	0.493	0.838	0.838	0.924	1.011	0.844	0.921	1.006	ns
D6	32	0	0.229	0.244	0.415	0.415	0.458	0.503	0.418	0.456	0.499	ns

#### Notes to Table 58:

(1) You can set this value in the Quartus II software by selecting D1, D2, D3, D5, and D6 in the Assignment Name column of Assignment Editor.

(2) Minimum offset does not include the intrinsic delay.

## **Programmable Output Buffer Delay**

Table 59 lists the delay chain settings that control the rising and falling edge delays of the output buffer. The default delay is 0 ps.

Table 59. Programmable Output Buffer Delay for Stratix V Devices (	Table 59.	Programmable Out	put Buffer Delay	y for Stratix V Devices (
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Symbol	Parameter	Typical	Unit
	Rising and/or falling edge delay	0 (default)	ps
D		25	ps
D <sub>OUTBUF</sub>		50	ps
		75	ps

Note to Table 59:

(1) You can set the programmable output buffer delay in the Quartus II software by setting the Output Buffer Delay Control assignment to either positive, negative, or both edges, with the specific values stated here (in ps) for the Output Buffer Delay assignment.

## Glossary

Table 60 lists the glossary for this chapter.

Table 60. Glossary (Part 1 of 4)

Letter	Subject	Definitions
Α		
В	—	—
С		
D	_	_
E	—	_
	f <sub>HSCLK</sub>	Left and right PLL input clock frequency.
F	f <sub>HSDR</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDR</sub> = 1/TUI), non-DPA.
	f <sub>hsdrdpa</sub>	High-speed I/O block—Maximum and minimum <b>LVDS</b> data transfer rate (f <sub>HSDRDPA</sub> = 1/TUI), DPA.

Letter	Subject	Definitions	
	V <sub>CM(DC)</sub>	DC common mode input voltage.	
	V <sub>ICM</sub>	Input common mode voltage—The common mode of the differential signal at the receiver.	
	V <sub>ID</sub>	Input differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the receiver.	
	V <sub>DIF(AC)</sub>	AC differential input voltage—Minimum AC input differential voltage required for switching.	
	V <sub>DIF(DC)</sub>	DC differential input voltage— Minimum DC input differential voltage required for switching.	
	V <sub>IH</sub>	Voltage input high—The minimum positive voltage applied to the input which is accepted by the device as a logic high.	
	V <sub>IH(AC)</sub>	High-level AC input voltage	
	V <sub>IH(DC)</sub>	High-level DC input voltage	
V	V <sub>IL</sub>	Voltage input low—The maximum positive voltage applied to the input which is accepted by the device as a logic low.	
	V <sub>IL(AC)</sub>	Low-level AC input voltage	
	V <sub>IL(DC)</sub>	Low-level DC input voltage	
	V <sub>OCM</sub>	Output common mode voltage—The common mode of the differential signal at the transmitter.	
	V <sub>OD</sub>	Output differential voltage swing—The difference in voltage between the positive and complementary conductors of a differential transmission at the transmitter.	
	V <sub>SWING</sub>	Differential input voltage	
	V <sub>X</sub>	Input differential cross point voltage	
	V <sub>OX</sub>	Output differential cross point voltage	
W	W	High-speed I/O block—clock boost factor	
X			
Υ	_	_	
Z			

#### Table 60. Glossary (Part 4 of 4)

# **Document Revision History**

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes	
June 2018	3.9	<ul> <li>Added the "Stratix V Device Overshoot Duration" figure.</li> </ul>	
April 2017		<ul> <li>Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "PS Timing Parameters for Stratix V Devices" table.</li> </ul>	
		<ul> <li>Changed the condition for 100-Ω R<sub>D</sub> in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table.</li> </ul>	
	3.8	<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>	
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>	
		<ul> <li>Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table.</li> </ul>	
luna 2016	3.7	<ul> <li>Added the V<sub>ID</sub> minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table</li> </ul>	
June 2016		<ul> <li>Added the I<sub>OUT</sub> specification to the "Absolute Maximum Ratings for Stratix V Devices" table.</li> </ul>	
December 2015	3.6	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.	
December 2015	3.5	<ul> <li>Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
		<ul> <li>Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table.</li> </ul>	
		• Changed the data rate specification for transceiver speed grade 3 in the following tables:	
		<ul> <li>"Transceiver Specifications for Stratix V GX and GS Devices"</li> </ul>	
		<ul> <li>"Stratix V Standard PCS Approximate Maximum Date Rate"</li> </ul>	
		<ul> <li>"Stratix V 10G PCS Approximate Maximum Data Rate"</li> </ul>	
July 2015		<ul> <li>Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
		<ul> <li>Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	
		<ul> <li>Changed the t<sub>co</sub> maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table.</li> </ul>	
		<ul> <li>Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>	